Notice of References Cited Application/Control No. 10/760,555 Examiner CongVan Tran Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0164848 A1	08-2004	Hwang et al.	340/005.82
*	В	US-2003/0115473 A1	06-2003	Sugimura et al.	713/186
*	С	US-6,256,737 B1	07-2001	Bianco et al.	713/186
*	D	US-6,145,083 A	11-2000	Shaffer et al.	726/7
*	Е	US-5,930,804 A	07-1999	Yu et al.	707/104.1
*	F	US-6,145,083 A	11-2000	Shaffer et al.	726/7
*	G	US-6,990,684 B2	01-2006	Futamura et al.	726/18
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.